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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/519,486	07/29/2005	Hiroaki Kurihara	Q85508	5314
23373 7590 10/10/2007 SUGHRUE MION, PLLC 2100 PENNSYLVANIA AVENUE, N.W.			EXAMINER	
			GETACHEW, ABIY	
	SUITE 800 WASHINGTON, DC 20037			PAPER NUMBER
			2841	
			MAIL DATE	DELIVERY MODE
	•		10/10/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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	Application No.	Applicant(s)				
	10/519,486	KURIHARA, HIROAKI				
Office Action Summary	Examiner	Art Unit				
	Abiy Getachew	2841				
The MAILING DATE of this communicate Period for Reply	ion appears on the cover sheet wi	th the correspondence address				
A SHORTENED STATUTORY PERIOD FOR WHICHEVER IS LONGER, FROM THE MAIL - Extensions of time may be available under the provisions of 37 after SIX (6) MONTHS from the mailing date of this communica- If NO period for reply is specified above, the maximum statutor - Failure to reply within the set or extended period for reply will, I Any reply received by the Office later than three months after the earned patent term adjustment. See 37 CFR 1.704(b).	ING DATE OF THIS COMMUNIC CFR 1.136(a). In no event, however, may a realtion. The period will apply and will expire SIX (6) MON by statute, cause the application to become AB	CATION. eply be timely filed THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed or	n <u>30 December 2004</u> .					
2a) This action is FINAL . 2b)	This action is FINAL . 2b)⊠ This action is non-final.					
•	- ''					
closed in accordance with the practice u	ınder <i>Ex parte Quayle</i> , 1935 C.D	. 11, 453 O.G. 213.				
Disposition of Claims						
4) ⊠ Claim(s) 1-12 is/are pending in the appl 4a) Of the above claim(s) is/are w 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) is/are rejected. 7) □ Claim(s) 1-12 is/are objected to: 8) □ Claim(s) are subject to restriction	vithdrawn from consideration.					
Application Papers						
9) The specification is objected to by the Example 10) The drawing(s) filed on 30 December 20 Applicant may not request that any objection Replacement drawing sheet(s) including the 11) The oath or declaration is objected to by	04 is/are: a) \square accepted or b) \square to the drawing(s) be held in abeyan correction is required if the drawing(ce. See 37 CFR 1.85(a). (s) is objected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119	1					
12) Acknowledgment is made of a claim for a a) All b) Some * c) None of: 1. Certified copies of the priority doc 2. Certified copies of the priority doc 3. Copies of the certified copies of the application from the International * See the attached detailed Office action for	cuments have been received. cuments have been received in A ne priority documents have been Bureau (PCT Rule 17.2(a)).	pplication No received in this National Stage				
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-83) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 12/30/04, 04/11/05.	948) Paper No(s	dummary (PTO-413) s)/Mail Date nformal Patent Application 				

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-12 are rejected under 35 U.S.C. 102(b) as being anticipated by Saito (US 2002/0048156 A1)

Regarding claim 1 Saito discloses a flexible wiring substrate (figure 14) comprising an insulating substrate (101), a wiring pattern (112) formed on a surface of the insulating substrate (101), and a solder resist layer [0059] covering a surface of the wiring pattern (112) excluding at least terminal portions of the wiring pattern (112), at least a portion of the outermost surface of the wiring pattern (112) which is not covered with the solder resist layer [0059] being provided with a tin-bismuth alloy plating layer (115 and 116), characterized in that the wiring pattern (112) comprises a base layer formed of a conductor and that a first tin plating layer (115) is provided on the base layer (See figure 14) so as to extend under a region covered with the solder resist layer [0059].

Regarding claim 2 as applied claim 1 Saito discloses wherein the first tin plating layer (115) of the wiring pattern (112) present under a region not covered with the solder resist layer [0059] is provided with a second tin plating layer (116), and at least a portion of the area of the second plating layer (116) is provided with the tin-bismuth

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alloy plating layer (115 and 116).

Regarding claim 3 as applied claim 1 Saito discloses wherein the first tin-plating layer (115) has a of 0.001 Mm to 0.6 Mm. [See section 0050]

Regarding claim 4 as applied claim 2 Saito discloses wherein the first tin plating layer has a thickness of 0.001 Mm to 0.6 Mm. [See section 0005] In re Aller, 105 USPQ 223.

Regarding claim 5 as applied claim 1 Saito discloses, wherein the first tin-plating layer has a thickness of 0.001 Mm to 0.2 Mm. [See section 0050] In re Aller, 105 USPQ 223.

Regarding claim 6 as applied claim 2 Saito discloses, wherein the first tin plating layer has a thickness of 0.001 Mm to 0.2 Mm. [See section 0050] In re Aller, 105 USPQ 223.

Regarding claim 7 as applied claims 5 or 6 Saito discloses wherein the first tin plating layer (115) is not subjected to heat treatment before provision of the solder resist layer [0059].

Regarding claim 8 as applied claims 1 or 6 Saito discloses wherein the wiring pattern (112) comprises a patterned copper layer and the first tin-plating layer formed on the copper layer [See section 0050].

Regarding claim 9 as applied claim 7 Saito discloses, wherein the wiring pattern comprises a patterned copper layer [See section 0005] and the first tin plating formed on the copper layer [See section 0050].

Regarding claim 10 Saito discloses A method for producing a flexible wiring (See

figure 14) substrate including an insulating substrate (101), a wiring pattern (112) formed on a surface of the insulating substrate (101), and a solder resist layer covering a surface (115 and 116) of the wiring pattern (112) excluding at least terminal portions of the wiring pattern (112), at least a portion of the outermost surface of the wiring pattern (112) which is not covered with the solder resist layer being provided with a tin-bismuth alloy plating layer (115,116), characterized in that the method comprises a step of forming a base layer of the wiring pattern (112) through patterning of a conductor layer [Section 0050] a step of forming a first tin plating layer on the base layer(101) a step of forming a solder resist layer (See figure 14) so as to cover the first tin plating layer such that a portion of the first tin plating layer is exposed a step of forming a second tin plating layer on a region of the first tin plating layer (115), which region is not covered with the solder resist layer [Sect6ion 0050] and a step of providing a tin-bismuth alloy plating layer on at least a portion of the region of the second tin plating layer (116).

Regarding claim 11 as applied claim 10 Saito discloses, wherein the first tinplating layer (115) is formed so as to have a thickness of 0.001 micro m to 0.6 micro m. [See section 0050]

Regarding claim 12 as applied claim 10 Saito discloses, wherein there are performed a step of forming the first tin plating layer so as to have a thickness of 0.001 micro m to 0.2 micro m and, subsequently, a step of forming the solder resist layer [0059] without performing heat treatment [Section 0061].

Conclusion

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Abiy Getachew whose telephone number is (571) 272 6932. The examiner can normally be reached on Monday to Friday 8Am to 4:30Pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Dean A. Reichard can be reached on (571) 272 1984. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Abiy Getachew Examiner Art Unit 2841

A.G. September 18, 2007

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